ALPHA & OMEGA SEMICONDUCTOR

AON3702

30V N-Channel MOSFET

SRFET™

General Description

SRFET™ AON3702 uses advanced trench technology with a monolithically integrated Schottky diode to provide excellent $R_{DS(ON)}$,and low gate charge. This device is suitable for use as a low side FET in SMPS, load switching and general purpose applications.

Product Summary

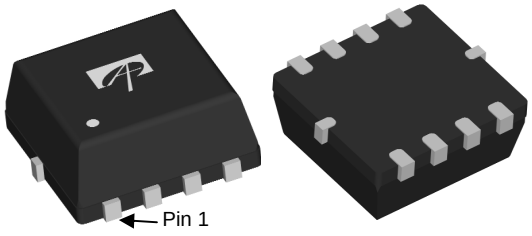
V_{DS} (V) = 30V
I_D =11A (V_{GS} = 10V)
$R_{DS(ON)}$ < 14.5mΩ (V_{GS} = 10V)
$R_{DS(ON)}$ < 18mΩ (V_{GS} = 4.5V)

100% Rg Tested

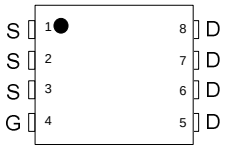
Green Product

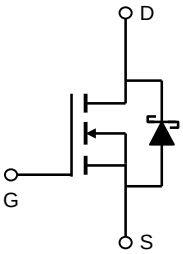
DFN 3x3

Top View **Bottom View**



Top View





SRFET™
Soft **R**ecovery MOS**FET**:
Integrated Schottky Diode

Absolute Maximum Ratings T_A=25°C unless otherwise noted

Parameter		Symbol	Maximum	Units
Drain-Source Voltage		V_{DS}	30	V
Gate-Source Voltage		V_{GS}	±12	V
Continuous Drain Current [A]	T_A=25°C	I_{DSM}	11	A
	T_A=70°C		9	
Pulsed Drain Current [B]		I_{DM}	60	
Power Dissipation	T_A=25°C	P_{DSM}	3.1	W
	T_A=70°C		2	
Junction and Storage Temperature Range		T_J, T_{STG}	-55 to 150	°C

Thermal Characteristics

Parameter		Symbol	Typ	Max	Units
Maximum Junction-to-Ambient [A]	t ≤ 10s	$R_{\theta JA}$	30	40	°C/W
Maximum Junction-to-Ambient [A]	Steady-State		65	80	°C/W
Maximum Junction-to-Lead [C]	Steady-State	$R_{\theta JL}$	20	25	°C/W

Electrical Characteristics (T_J=25°C unless otherwise noted)

Symbol	Parameter	Conditions	Min	Typ	Max	Units
STATIC PARAMETERS						
BV_{DSS}	Drain-Source Breakdown Voltage	I_D=250uA, V_{GS}=0V	30			V
I_{DSS}	Zero Gate Voltage Drain Current	V_{DS}=24V, V_{GS}=0V		0.01	0.1	mA
		T_J=125°C		4	10	
I_{GSS}	Gate-Body leakage current	V_{DS}=0V, V_{GS}= ±12V			0.1	µA
$V_{GS(th)}$	Gate Threshold Voltage	V_{DS}=V_{GS} I_D=250µA	1.5	1.9	2.4	V
$I_{D(ON)}$	On state drain current	V_{GS}=4.5V, V_{DS}=5V	60			A
$R_{DS(ON)}$	Static Drain-Source On-Resistance	V_{GS}=10V, I_D=11A		12	14.5	mΩ
		T_J=125°C		19	24	
		V_{GS}=4.5V, I_D=10A		15	18	mΩ
g_{FS}	Forward Transconductance	V_{DS}=5V, I_D=11A		64		S
V_{SD}	Diode Forward Voltage	I_S=1A,V_{GS}=0V		0.38	0.5	V
I_S	Maximum Body-Diode + Schottky Continuous Current				5.0	A
DYNAMIC PARAMETERS						
C_{iss}	Input Capacitance	V_{GS}=0V, V_{DS}=15V, f=1MHz		1450	1885	pF
C_{oss}	Output Capacitance			224		pF
C_{rss}	Reverse Transfer Capacitance			92		pF
R_g	Gate resistance	V_{GS}=0V, V_{DS}=0V, f=1MHz		1.6	3.0	Ω
SWITCHING PARAMETERS						
Q_g(10V)	Total Gate Charge	V_{GS}=10V, V_{DS}=15V, I_D=11A		24.0	31	
Q_g(4.5V)	Total Gate Charge			12.0		nC
Q_{gs}	Gate Source Charge			3.9		nC
Q_{gd}	Gate Drain Charge			4.2		nC
$t_{D(on)}$	Turn-On DelayTime	V_{GS}=10V, V_{DS}=15V, R_L=1.4Ω, R_{GEN}=3Ω		5.5		ns
t_r	Turn-On Rise Time			4.7		ns
$t_{D(off)}$	Turn-Off DelayTime			24.0		ns
t_f	Turn-Off Fall Time			4.0		ns
t_{rr}	Body Diode Reverse Recovery Time	I_F=11A, dI/dt=300A/µs		10	12	ns
Q_{rr}	Body Diode Reverse Recovery Charge	I_F=11A, dI/dt=300A/µs		6.8		nC

A: The value of $R_{\theta JA}$ is measured with the device in a still air environment with T_A =25°C. The power dissipation P_{DSM} and current rating I_{DSM} are based on $T_{J(MAX)}$=150°C, using t ≤ 10s junction-to-ambient thermal resistance.

B: Repetitive rating, pulse width limited by junction temperature $T_{J(MAX)}$=150°C.

C. The $R_{\theta JA}$ is the sum of the thermal impedence from junction to lead R θJL and lead to ambient.

D. The static characteristics in Figures 1 to 6 are obtained using <300 us pulses, duty cycle 0.5% max.

E. These tests are performed with the device mounted on 1 in 2 FR-4 board with 2oz. Copper, in a still air environment with T_A=25°C. The SOA curve provides a single pulse rating.

Rev1:Nov. 2010

TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

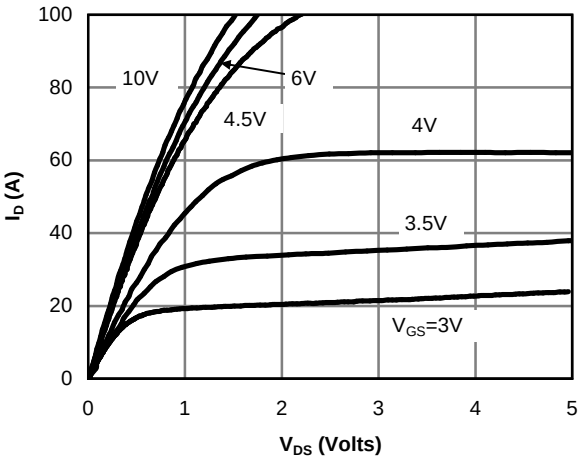


Figure 1: On-Region Characteristics

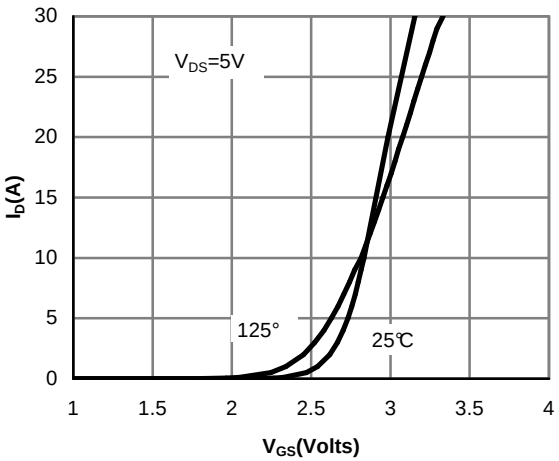


Figure 2: Transfer Characteristics

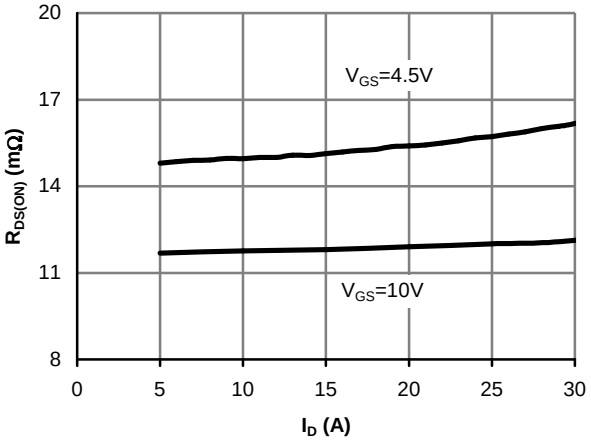


Figure 3: On-Resistance vs. Drain Current and Gate Voltage

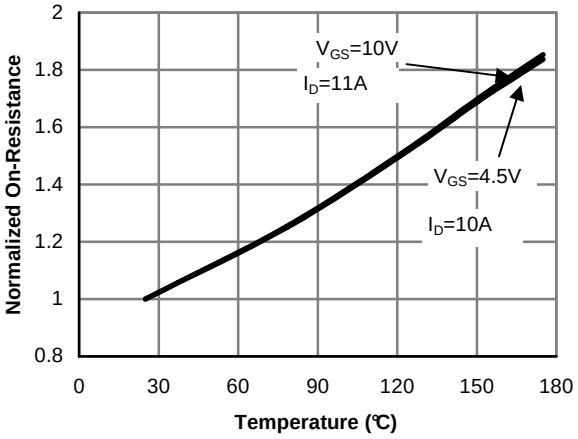


Figure 4: On-Resistance vs. Junction Temperature

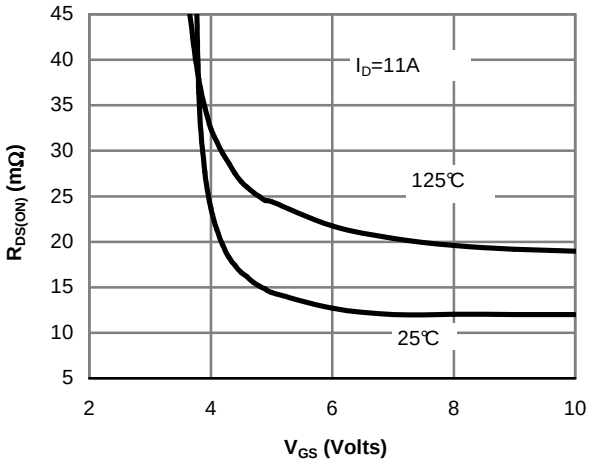


Figure 5: On-Resistance vs. Gate-Source Voltage

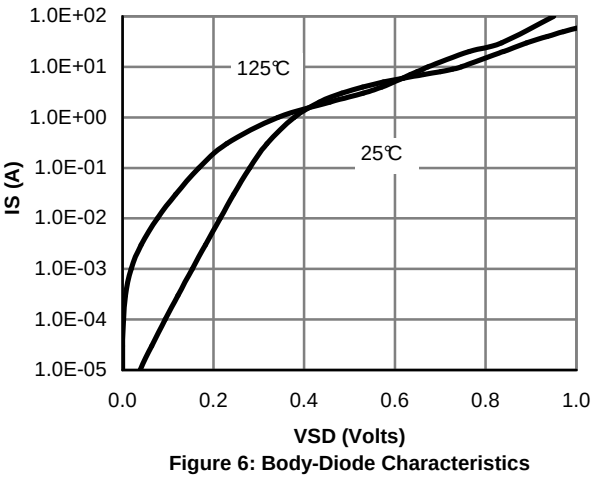


Figure 6: Body-Diode Characteristics

TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

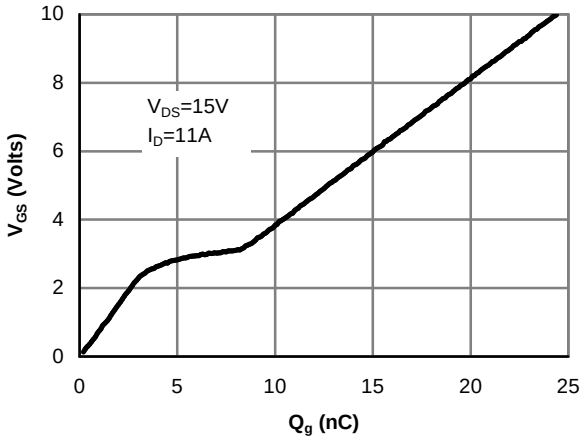


Figure 7: Gate-Charge Characteristics

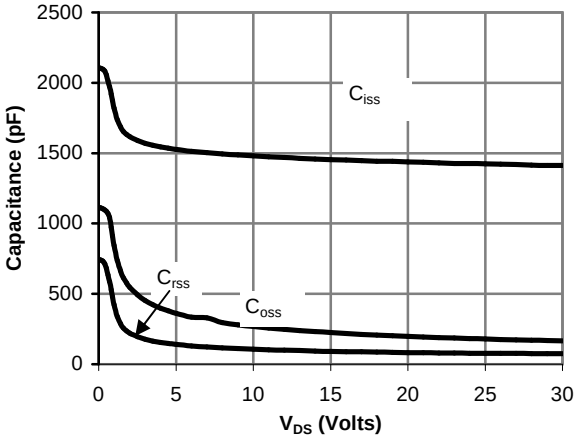


Figure 8: Capacitance Characteristics

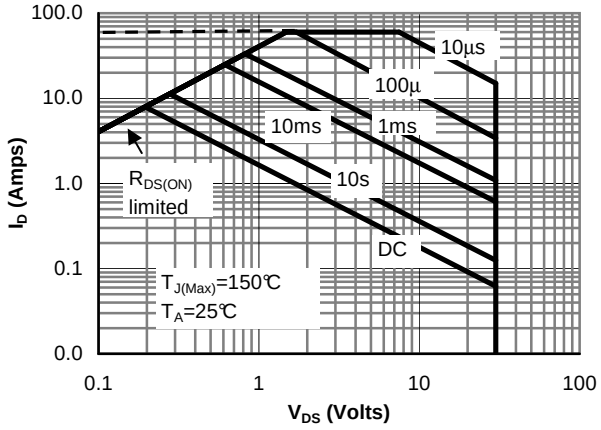


Figure 9: Maximum Forward Biased Safe Operating Area (Note E)

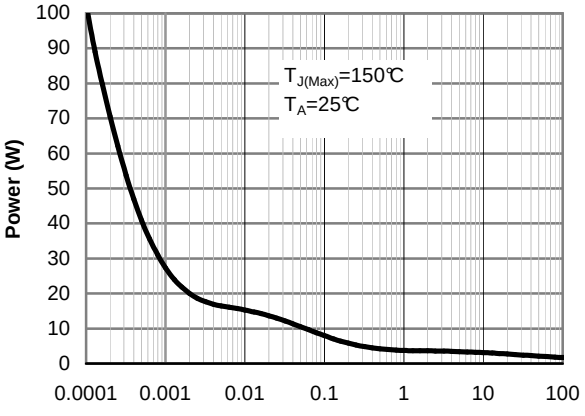


Figure10: Single Pulse Power Rating Junction-to-Ambient (Note E)

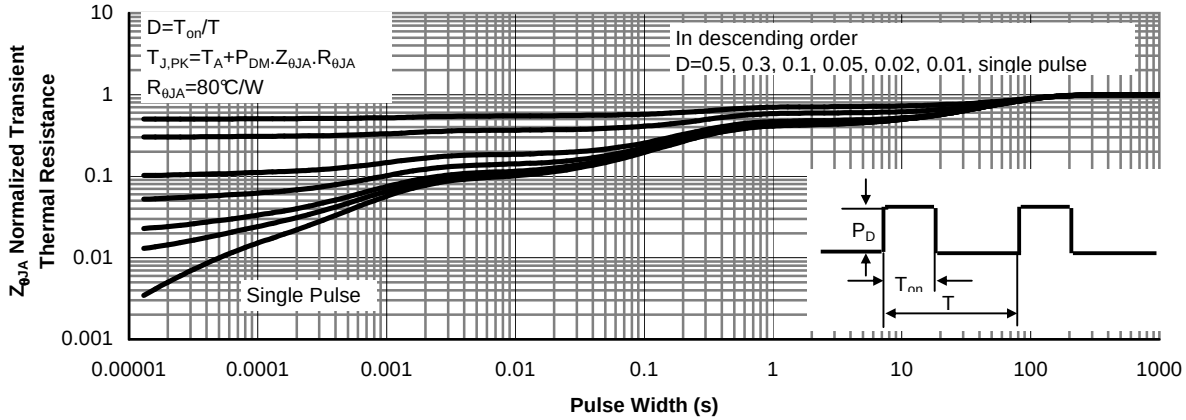


Figure 11: Normalized Maximum Transient Thermal Impedance (Note E)

TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

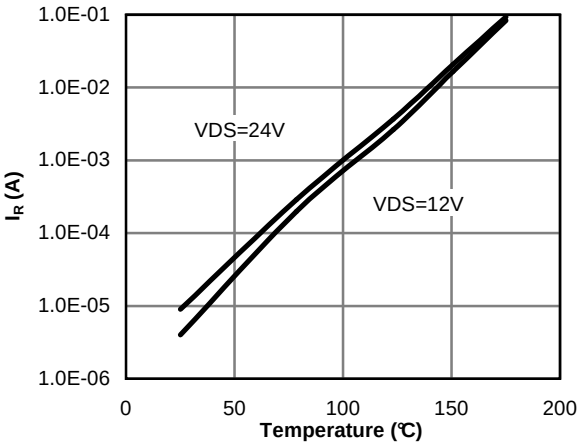


Figure 12: Diode Reverse Leakage Current vs. Junction Temperature

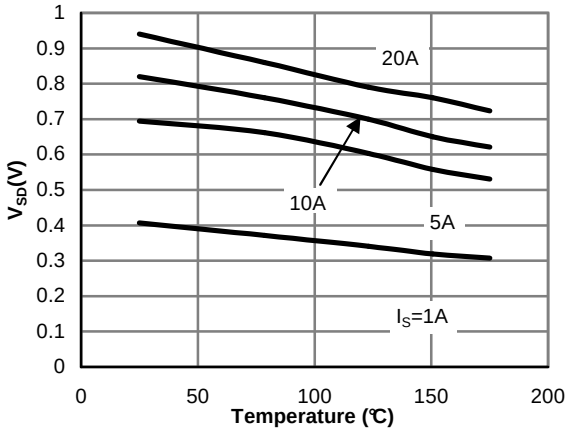


Figure 13: Diode Forward voltage vs. Junction Temperature

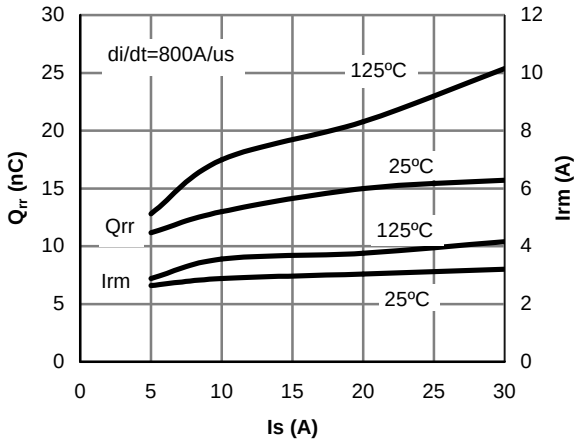


Figure 14: Diode Reverse Recovery Charge and Peak Current vs. Conduction Current

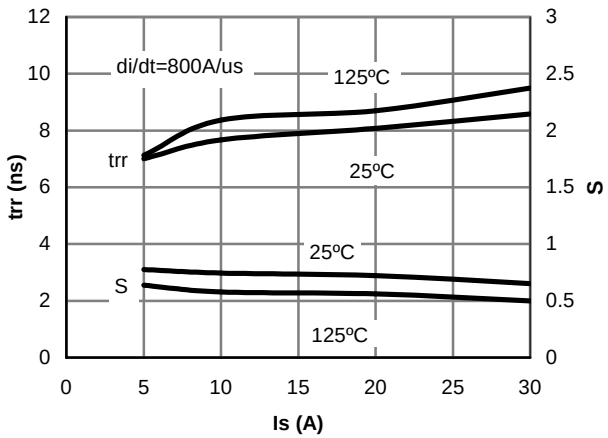


Figure 15: Diode Reverse Recovery Time and Soft Coefficient vs. Conduction Current

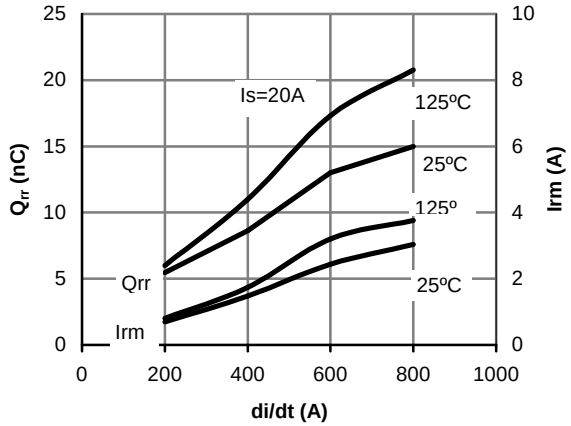


Figure 16: Diode Reverse Recovery Charge and Peak Current vs. di/dt

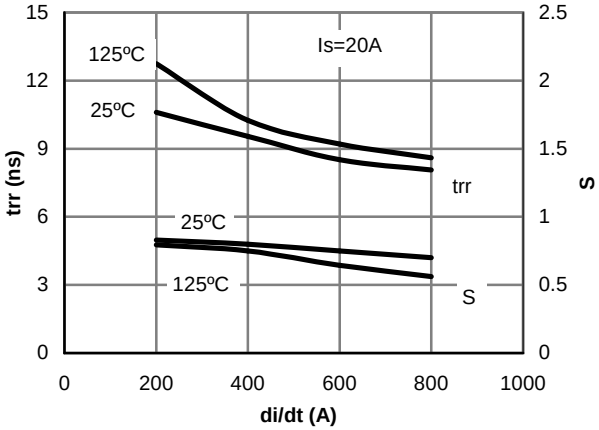


Figure 17: Diode Reverse Recovery Time and Soft Coefficient vs. di/dt